Ⓚ Kurz-Kasch, Inc.
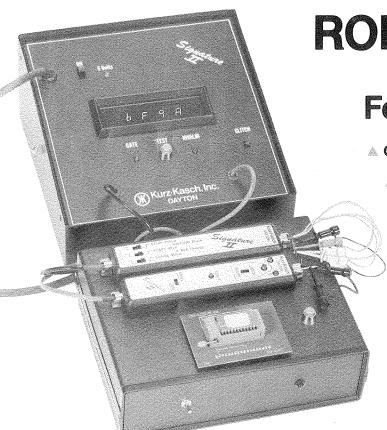
Quality Test & Measurement Instruments

ROM Test 1™

Features

▲ One-step testing of ROM's

▲ Eliminates circuit probing

▲ Built-in self test

▲ Use with any Signature Analyzer

Checks 64K ROM's in 2 seconds

The Kurz-Kasch Signature II™ has revolutionized digital-circuit testing. But with ROM Test 1, we've brought Signature Analysis a step further. You can now check any ROM device (ROM's, PROM's, EPROM's etc.) with up to 64K memory without in-circuit probing of each data line. You read only one signature for a "good" or "no-good" test. The ROM Test 1 cuts testing time to approximately 2 seconds to reduce your service-call costs. Or to give you easy one-step testing of incoming chips or program verification.

And it's so simple to use there's virtually no training. You simply connect the ROM Test 1 to the Signature II probes and install a "personality" board compatible with the device to be tested.

Now you can insert memory chip after memory chip in the personality board and check each device by reading only one signature. And there's a built-in test. Each "personality" board displays a certain signature to let you know that everything is working before testing. Testing of ten 64K devices normally requires probing 80 data lines and reading 80 signatures. Now there is no probing and ten signatures verify operation.

Of course we'd like you to use our Signature II with the ROM Test 1, but ROM Test 1 is compatible with any other Signature Analyzer currently in use. Too good to be true? Write or give us a call for full details. Kurz-Kasch, Inc. 2271 Arbor Blvd., Dayton, Ohio 45439, 513/299-0990.

Specifications

Processor: Type Z80.

Clock: 20 nanoseconds rise and fall time.

Address: 10 nanoseconds rise and fall time.

Clock Frequency: 1 MHz.

Error Detection: Single signature for $D_0 \ldots D_n$.

Error Detection Probability: Single-bit errors 100%, multiple-bit errors 99.998%.

Device-Under-Test Inputs: Buffered.

Device-Under-Test Outputs: Buffered.

Test Capability: Any read-only memory up to 64K (ROM, PROM, EPROM, EAROM).

Internal Voltages: ±5 volts, +12 volts. Provision for −12 volts with kit if needed.

Standby Voltage: ±1.3 volts.

Test Time: Approximately 2 seconds maximum.

For product improvement, specifications are subject to change without notice.

To use the ROM Test 1,™ just follow these easy steps.

(1) Place the Signature II™ pod in clips toward the rear of the ROM Test 1™ with the E-Z hooks to the right.

(2) Connect the ground (black) E-Z hook to ground.
Connect the START (blue) E-Z hook to START.
Connect the STOP (yellow) E-Z hook to STOP.
Connect the CLOCK (white) E-Z hook to CLOCK.

(3) Place the Data probe in the foremost clips and connect the probe tip to the DATA input.

(4) Place the START, STOP, and CLOCK switches (on pod) in the "rising" position.

(5) Select the correct PB (personality board) for the device to be tested.

(6) Plug in the PB, being careful not to bend the pins. The lock lever should be up and to the left when facing the ROM Test 1. The lock lever is the indicator for pin 1 of the device under test (DUT).

(7) Turn ON the Signature II and the ROM Test 1. The LED on the front of the ROM Test 1 does not come ON unless the test button is pressed. Press this button and observe the LED. A signature will be displayed. This signature provides a built-in self test (each PB will have a different signature) that verifies the hook-up and equipment operation.

(8) Place the DUT in the socket and pull the locking lever to the horizontal position.

(9) Press the "test" button and read the DUT signature.